	Search Notes			
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Application/Control No.	Applicant(s)/Patent under Reexamination
10/531,884	HAIGH ET AL.
Examiner	Art Unit
Karen Cheng	1626

SEARCHED				
Class	Subclass	. Date	Examiner	
514	422	7/17/2007	кс	
548	517	7/17/2007	кс	
548	518	7/17/2007	кс	
-				

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
514	422	7/17/2007	кс		
548	517, 518	7/17/2007	кс		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST Search (including Interference, see attached)	7/17/2007	кс